

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/757,974	TIHANYI, JENOE	
Examiner		Art Unit		Page 1 of 1
Hiep Nguyen		2816		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0006829	01-2003	Alessandria et al.	327/538
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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*	A	US-2003/0006829	01-2003	Alessandria et al.	327/538
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